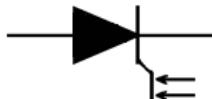




High-end Power Semiconductor Manufacturer

**TL183-2000****Light Triggered Thyristor**

- ◆  $V_{DRM} = \underline{6000 - 6400V}$
- ◆  $V_{RRM} = \underline{6000 - 6400V}$
- ◆  $I_{T(AV)} = \underline{1685 A}$  ( $T_C = 85^\circ C$ )
- ◆  $I_{T(AV)} = \underline{2115 A}$  ( $T_C = 70^\circ C$ )
- ◆  $I_{TSM} = \underline{40 kA}$  ( $T_j = 120^\circ C$ )
- ◆  $P_{LM} = \underline{40 mW}$

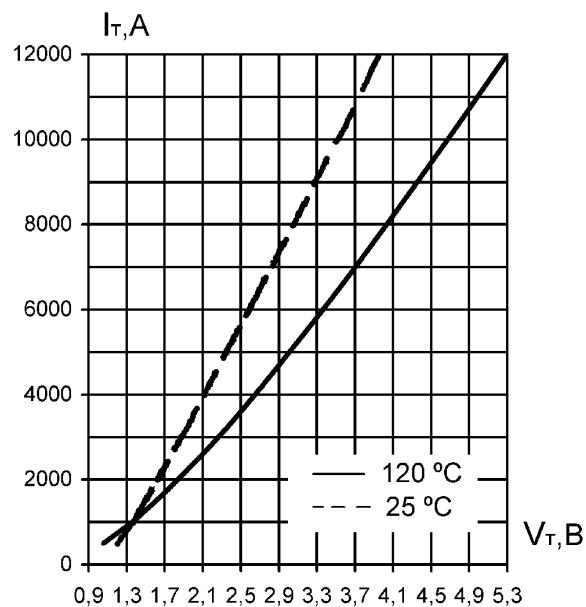


- ◆ Light triggering
- ◆ Low on-state and switching losses
- ◆ Interdigitated amplifying gate
- ◆ Acceptable for series and parallel connections (low dispersion  $Q_{rr}$ ,  $U_{TM}$ )

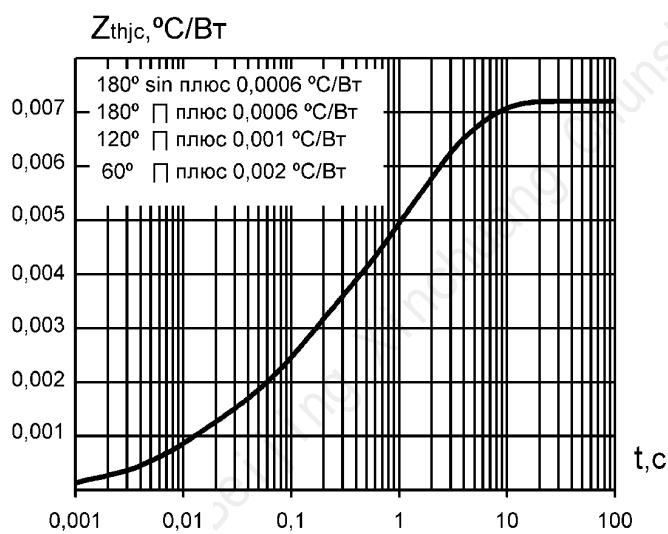
#### MAXIMUM RATED VALUES

Parameters and conditions	Symbol	Values	Units
Repetitive peak off-state voltage	$V_{DRM}$	6000, 6200, 6400	V
Repetitive peak reverse voltages	$V_{RRM}$	6000, 6200, 6400	
Repetitive peak off-state current / Repetitive peak reverse current $T_j=120^\circ C$ , $V_D/V_R = V_{DRM}/V_{RRM}$	$I_{DRM} / I_{RRM}$	max.250	mA
Maximum average on-state current $f = 50$ Hz, double side cooling $T_C=85^\circ C$ $T_C=70^\circ C$	$I_{T(AV)}$	1685 2115	A
RMS on-state current, $f=50$ Hz, $T_C=70^\circ C$	$I_{TRMS}$	3320	
Surge current, $V_R=0$ V, $T_j = 120^\circ C$ , $t_p=10$ ms	$I_{TSM}$	40	
Safety current, $T_j=120^\circ C$ , $t_p=10$ ms	$I^2t$	8000	$kA^2s$
Critical rate of rise of on-state current, $V=0.67V_{DRM}$ , $I_T=4000$ A, $P_{LM}=40$ mW, $t_L=10\ \mu s$ , $t_{rise}=0.5\ \mu s$ , $f=50$ Hz, $T_j=120^\circ C$	$(dI_T/dt)_{crit}$	300	A/ $\mu s$
Critical rate of rise of off-state voltage, $V_D = 0.67V_{DRM}$ , $T_j = 120^\circ C$	$(dV_D/dt)_{crit}$	1000, 1600, 2000	V/ $\mu s$
Minimum gate trigger light power, $T_j = 25^\circ C$ , $V_D = 12$ V	$P_{LM}$	max. 40	mW
Operating temperature	$T_j$	-40... +120	$^\circ C$
Storage temperature	$T_{stg}$	-40... +50	

<b>ELECTRICAL CHARACTERISTICS</b>			
Maximum peak on-state voltage, $I_T = 6280 \text{ A}, T_j = 25 \text{ }^\circ\text{C}$	$V_{TM}$	max. 2.65	V
On-state threshold voltage, $T_j = 120 \text{ }^\circ\text{C}, I_T = 3000 - 9500 \text{ A}$	$V_{(TO)}$	max. 1.2	
On-state slope resistance, $T_j = 120 \text{ }^\circ\text{C}, I_T = 3000 - 9500 \text{ A}$	$r_T$	max. 0.35	$\text{m}\Omega$
Gate controlled delay time, $V = 1000 \text{ V}, I_T = 2000 \text{ A}, P_{LM} = 40 \text{ mW}, t_L = 10 \mu\text{s}, t_{rise} = 0.5 \mu\text{s}, T_j = 25 \text{ }^\circ\text{C}$	$t_d$	max. 5.0	$\mu\text{s}$
Circuit-commutated turn-off time, $I_T = 2000 \text{ A}, \frac{dI_T}{dt} = -5 \text{ A}/\mu\text{s}, V_R \geq 100 \text{ V}, V_D = 0.67V_{DRM}, (dV_D/dt) = 50 \text{ V}/\mu\text{s}, T_j = 120 \text{ }^\circ\text{C}$	$t_q$	typ. 630	
Recovery charge, $\frac{dI_T}{dt} = -5 \text{ A}/\mu\text{s}, T_j = 120 \text{ }^\circ\text{C}, I_T = 2000 \text{ A}, V_R \geq 100 \text{ V}$	$Q_{rr}$	max. 5000	$\mu\text{As}$
Holding current, $V_D = 12 \text{ V}, T_j = 25 \text{ }^\circ\text{C}$	$I_H$	100	$\text{mA}$
Latching current, $V_D = 12 \text{ V}, T_j = 25 \text{ }^\circ\text{C}, P_{LM} = 40 \text{ mW}, t_L = 10 \mu\text{s}, t_{rise} = 0.5 \mu\text{s}$	$I_L$	1000	
<b> THERMAL PARAMETERS</b>			
Thermal resistance junction to case, sin 180°: double side cooled DC: double side cooled DC: anode side cooled DC: cathode side cooled	$R_{thjc}$ $R_{thjc}$ $R_{thjc-A}$ $R_{thjc-K}$	0.0078 0.0072 0.0112 0.0201	$^\circ\text{C/W}$
Thermal resistance case to heatsink, double side cooled single side cooled	$R_{thch}$	0.002 0.004	
<b>MECHANICAL PARAMETERS</b>			
Weight	$w$	typ. 2.0	kg
Clamping force	$F$	60 - 80	kN
Vibration resistance	$a$	50	$\text{m}/\text{s}^2$
Creepage distance	$D_s$	36	mm
Air strice distance	$D_a$	23	mm



**Fig. 1. Limiting on-state characteristic  $i_T = f(v_T)$**



**Fig. 2. Transient thermal impedance  $Z_{thJC} = f(t)$  for DC**

#### On-state characteristics model

$$V_T = A + B \cdot I_T + C \cdot \ln(I_T + 1) + D \cdot \sqrt{I_T}$$

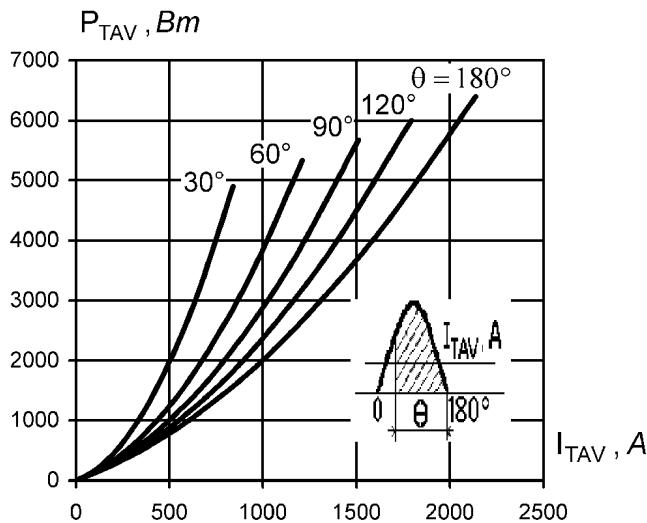
valid for  $I_T = 500 - 12000$  A

	$T_j = 120$ °C	$T_j = 25$ °C
A	0.427	0.583
B	0.0002137	0.0002311
C	0.012	0.087
D	0.02	-0.001815

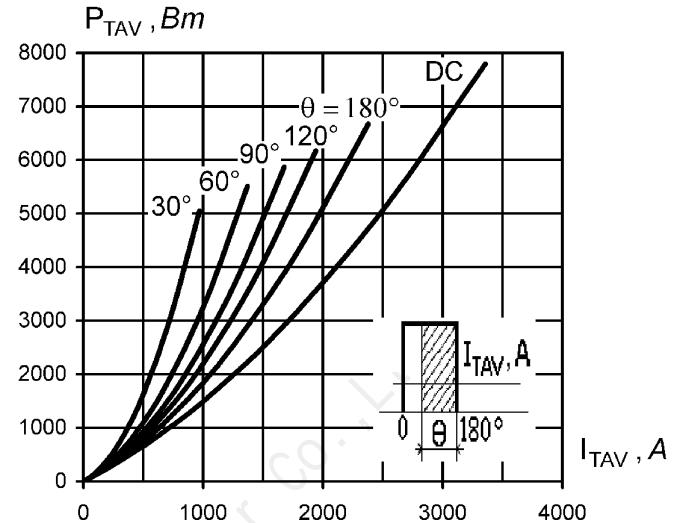
#### Analytical elements of transient thermal impedance, junction to case

$$Z_{thjc} = \sum_{i=1}^n R_i (1 - e^{-t/\tau_i})$$

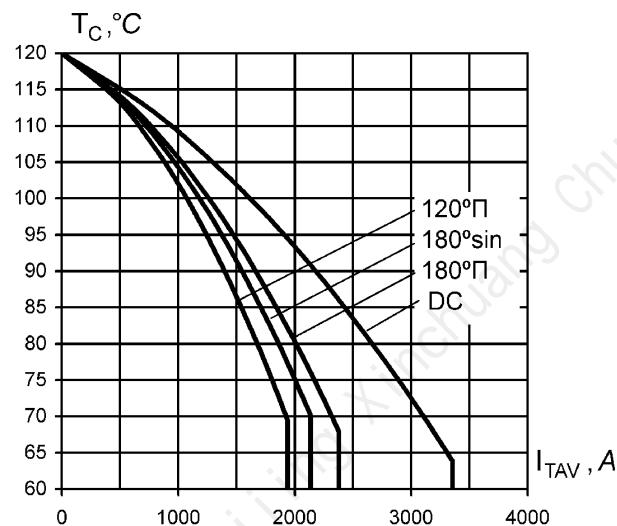
i	1	2	3	4	5
$R_i$ , °C/BT	0,00027	0,0008	0,0018	0,0023	0,00203
$\tau_{i,c}$	0,0041	0,013	0,11	0,86	3,56



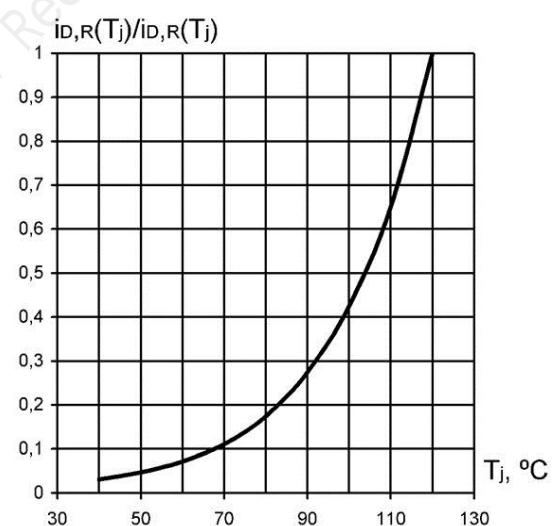
**Fig. 3. On-state power loss vs. On-state current (sine)**



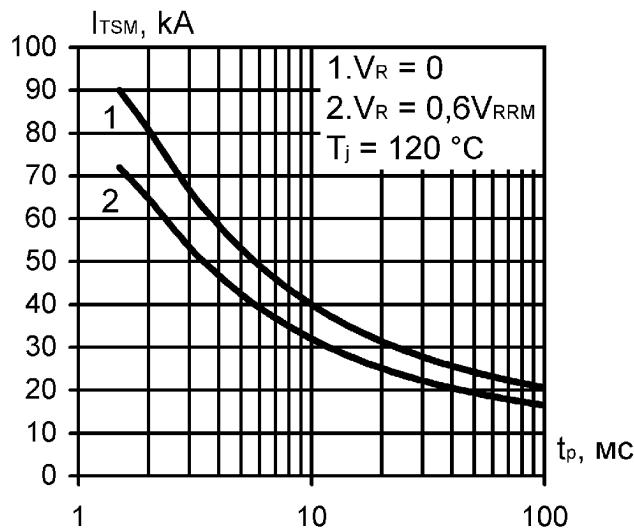
**Fig. 4. On-state power loss vs. on-state current (rectangular)**



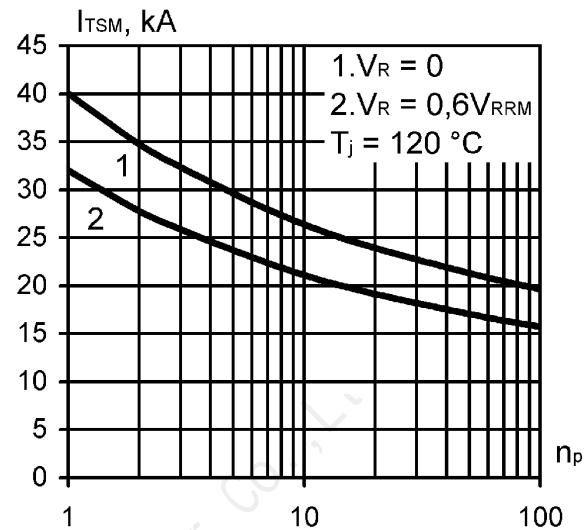
**Fig. 5. Maximum allowable case temperature during various angles of conductance and various forms of current**



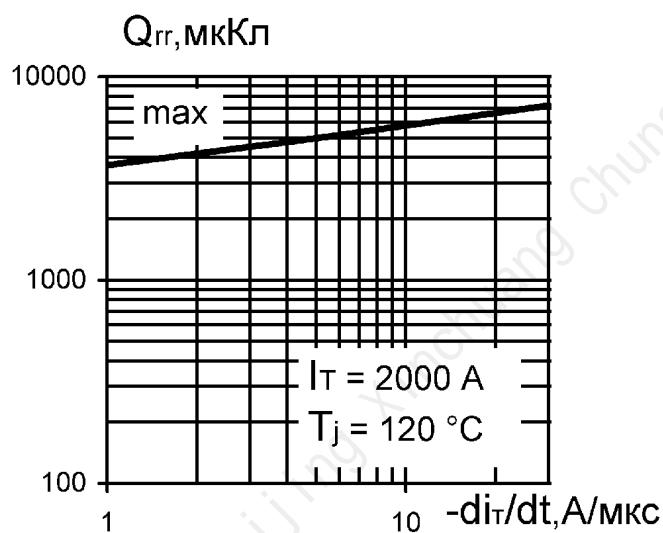
**Fig. 6. Repetitive peak off-state current and repetitive peak reverse current vs. junction temperature ( $U_D=U_{DRM}$   $U_R=U_{RRM}$ )**



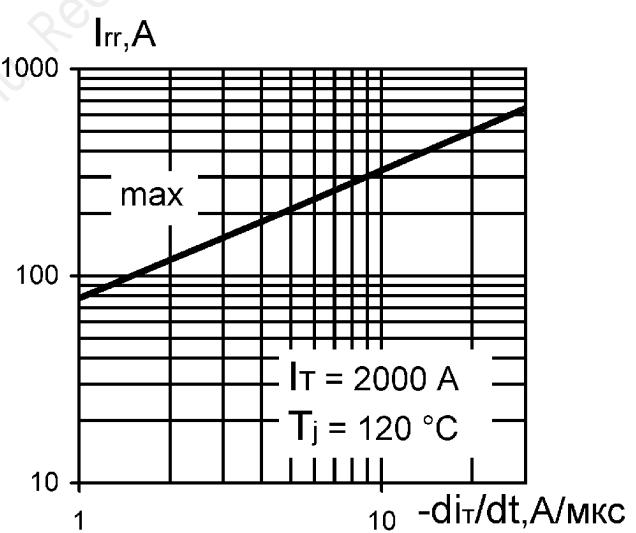
**Fig. 7. Surge on-state current vs. pulse length (half-sine)**



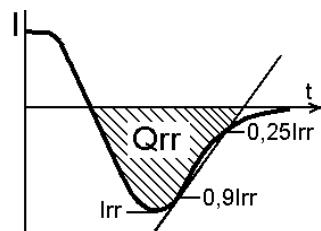
**Fig. 8. Surge on-state current vs. number of pulses of sine form (10 ms, 50 Hz)**

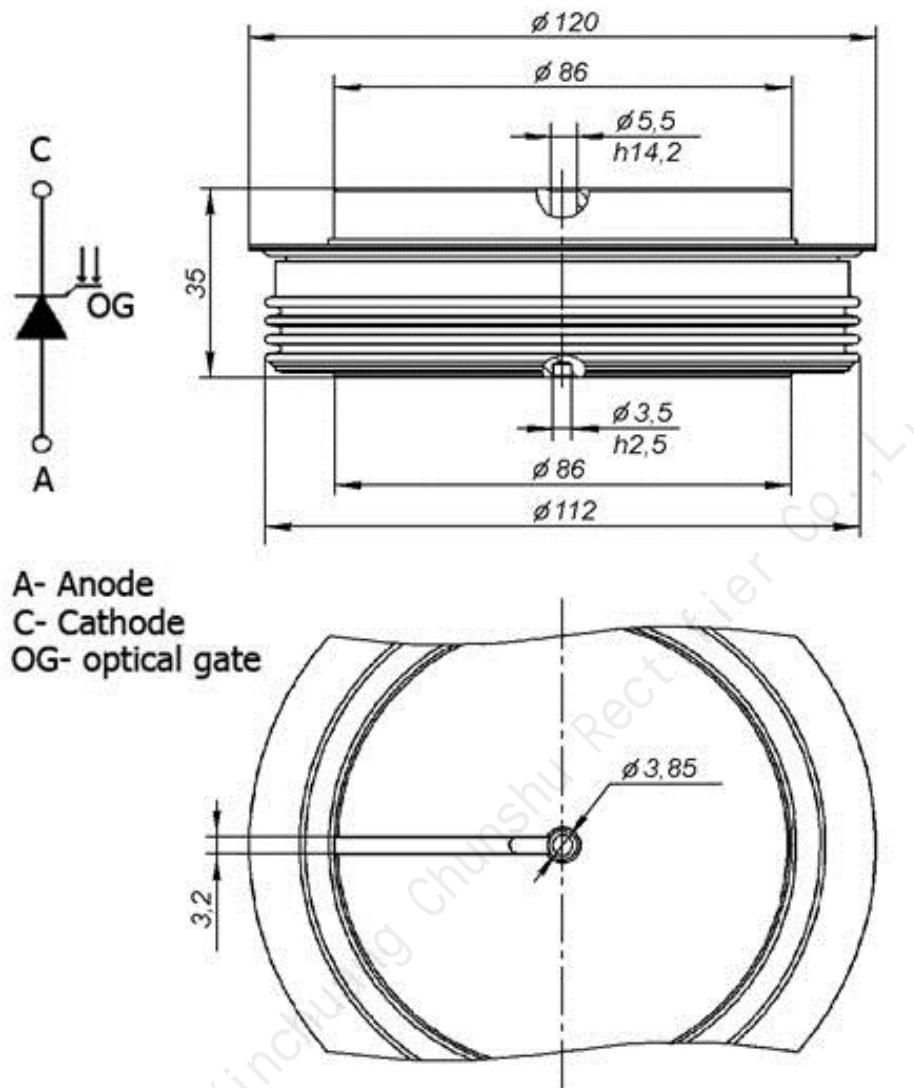


**Fig. 9. Recovery charge vs. decay rate of on-state current**



**Fig. 10. Peak reverse recovery current vs. decay rate of on-state current**





**Fig. 11. Device Outline Drawing  
(dimensions in mm)**